Special Issue

Reliability and Fault Tolerance Techniques in Emerging Technologies

Message from the Guest Editors

The focus of this Special Issue is on the advancements in reliability and fault tolerance techniques for emerging semiconductor technologies, including three-dimensional technologies (such as 2.5D/3D Integrated Circuits), nanoscale FinFET devices, innovative memories (such as PCRAM, STTMRAM, RRAM), introducing state-of-the-art investigations on the methods and techniques as well as modern implementation technologies enabling an effective and efficient development of highly reliable systems and designs. The topics of interest include but are not limited to all the following topics applied to emerging semiconductor technologies:

- Design for Reliability
- Design for Single Event Effect Hardening
- Single Event Effect Modeling, Analysis, and Mitigation
- Modeling and Analysis of Radiation Effect
- Hardening Techniques for Transient Errors
- CAD Tools for 3D Technologies
- Design and Test for 2.5D/3D ICs
- Design and Test for 3D memories
- Design and Test for Emerging Memory Technologies

Guest Editors

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Deadline for manuscript submissions

closed (30 November 2021)

Electronics

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Impact Factor 2.6
CiteScore 6.1

mdpi.com/si/87850

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About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guestedited by leading experts in selected topics of interest.

Editor-in-Chief

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